

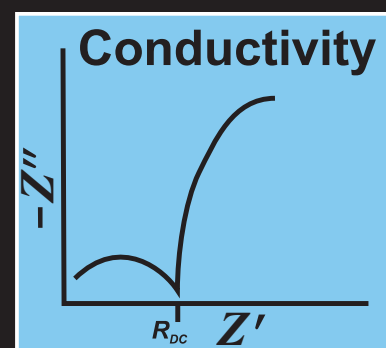
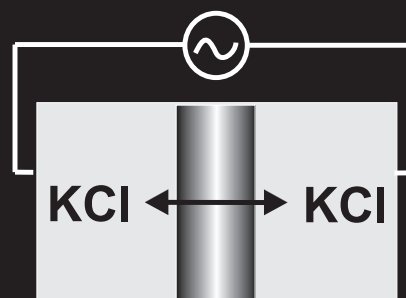
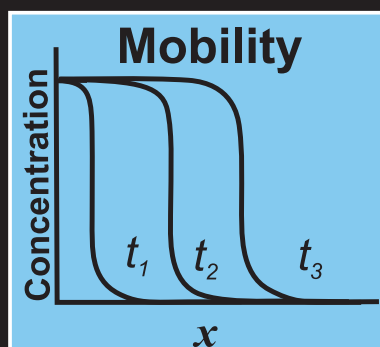
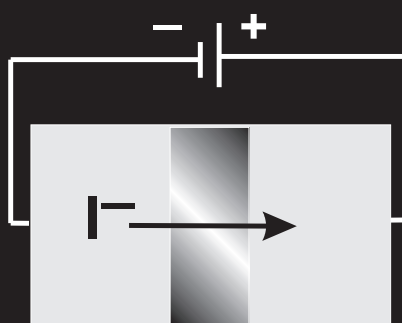
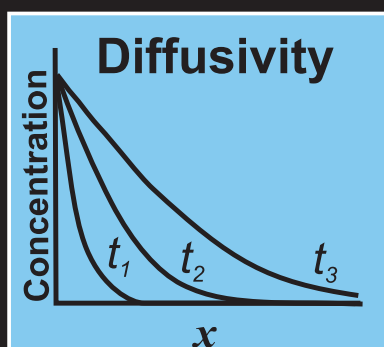
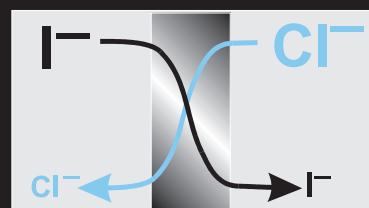


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<sup>1</sup>At Boulder, CO 80303.

<sup>2</sup>Some elements at Boulder, CO.

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**Cover:** The three most common experimental methods used to estimate the diffusive transport coefficient of porous building materials are diffusivity, mobility, and conductivity measurements. The diffusivity and mobility measurements require on the order of weeks to months to perform for some concretes, while a conductivity measurement can be performed in a matter of minutes on the same materials. The paper by Snyder et al. (p. 497) investigates the viability of using a standardized conduction test method (ASTM C 1202), with a trivial procedural modification, to determine specimen conductivity by comparing the results to impedance spectroscopy measurements. (Cover illustration by C. Carey.)

The *Journal of Research of the National Institute of Standards and Technology*, the flagship periodic publication of the national metrology institute of the United States, features advances in metrology and related fields of physical science, engineering, applied mathematics, statistics, and information technology that reflect the scientific and technical programs of the Institute. The *Journal* publishes papers on instrumentation for making accurate measurements, mathematical models of physical phenomena, including computational models, critical data, calibration techniques, well-characterized reference materials, and quality assurance programs that report the results of current NIST work in these areas. Occasionally, a Special Issue of the *Journal* is devoted to papers on a single topic. Also appearing on occasion are review articles and reports on conferences and workshops sponsored in whole or in part by NIST.

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